

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	<b>Docket Number (Optional)</b> <b>TWI-8570</b>	<b>Application Number</b> <b>NEW</b>
	<b>Applicant(s)</b> <b>Michial Duff Howell et al.</b>	
	<b>Filing Date</b> <b>HEREWITH</b>	<b>Group Art Unit</b> <b>Unknown</b>

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
Jf	*AA	3,887,392	06/03/1975	Tang	134	1	11/23/1973
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	*AI	5,449,411	09/12/1995	Fukuda et al.	118	723 MP	10/19/1993
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							YES	NO
Jf	*AQ	4-357836	06/04/1991	Japan (translation included)	H01L	21/304	X	
	*AR	0 462 459	06/07/1991	EPC	H01L	21/00		
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	*AT	WO 95/00681	01/05/1995	PCT	C23G	1/00		
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	*AV	WO 98/05066	02/05/1998	PCT	H01L	21/66		
Jf	*AW	WO 99/02970	01/21/1999	PCT	G01N	21/21		
	*AX	WO 99/356677	07/15/1999	PCT	H01L	21/306		

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Jf	*AY	K. Imen, S.J. Lee & S.D. Allen, "Laser-assisted micron scale particle removal," <i>Appl. Phys. Lett.</i> , Vol 58, No. 2, 14 January 1991, pp. 203-205.
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<b>Examiner</b> <i>Shauntina Ingua</i>	<b>Date Considered</b> <i>5/2/04</i>
<b>Examiner:</b> Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	